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APPLICATION NO.	FILI	NG DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/634,123	08/	/04/2003	Edmund Koon Tian Lua	2269-5709US (02-1462.00/U	5763
24247	7590	10/20/2005		EXAMINER	
TRASK BI	RITT			ANDUJAR, LEONARDO	
P.O. BOX 2				ART UNIT	PAPER NUMBER
SALT LAKE CITY, UT 84110					
				2826	

DATE MAILED: 10/20/2005

Please find below and/or attached an Office communication concerning this application or proceeding.

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	Application No.	Applicant(s)	4VC
Office Action Summany	10/634,123	LUA ET AL.	
Office Action Summary	Examiner	Art Unit	
	Leonardo Andújar	2826	
The MAILING DATE of this communication ap Period for Reply	pears on the cover sheet w	ith the correspondence address	\$
A SHORTENED STATUTORY PERIOD FOR REPL THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1. after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a rep - If NO period for reply is specified above, the maximum statutory period - Failure to reply within the set or extended period for reply will, by statut Any reply received by the Office later than three months after the mailir earned patent term adjustment. See 37 CFR 1.704(b).	136(a). In no event, however, may a ply within the statutory minimum of this will apply and will expire SIX (6) MOI te, cause the application to become A	reply be timely filed ty (30) days will be considered timely. NTHS from the mailing date of this communi BANDONED (35 U.S.C. § 133).	iication.
Status		•	
 Responsive to communication(s) filed on 7/29 This action is FINAL. 2b) This Since this application is in condition for allowed closed in accordance with the practice under the second seco	s action is non-final. ance except for formal mat	• •	rits is
Disposition of Claims			
 4) Claim(s) 26-38 and 40-46 is/are pending in the 4a) Of the above claim(s) is/are withdra 5) Claim(s) 38 and 41-46 is/are allowed. 6) Claim(s) 26,27,30-37 and 40 is/are rejected. 7) Claim(s) 28 and 29 is/are objected to. 8) Claim(s) are subject to restriction and/or 	awn from consideration.		
Application Papers			
9) ☐ The specification is objected to by the Examina 10) ☑ The drawing(s) filed on 04 August 2003 is/are: Applicant may not request that any objection to the Replacement drawing sheet(s) including the correct 11) ☐ The oath or declaration is objected to by the E	a) \boxtimes accepted or b) \square of a drawing(s) be held in abeyant of the drawing	nce. See 37 CFR 1.85(a). I(s) is objected to. See 37 CFR 1.1	
Priority under 35 U.S.C. § 119			
12) ☒ Acknowledgment is made of a claim for foreign a) ☒ All b) ☐ Some * c) ☐ None of: 1. ☒ Certified copies of the priority documen 2. ☐ Certified copies of the priority documen 3. ☐ Copies of the certified copies of the priority documen application from the International Burea * See the attached detailed Office action for a list	its have been received. Its have been received in A prity documents have been au (PCT Rule 17.2(a)).	Application No received in this National Stag	e
Attachment(s)			
1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08 Paper No(s)/Mail Date	Paper No	Summary (PTO-413) s)/Mail Date Informal Patent Application (PTO-152) 	ı

DETAILED ACTION

Acknowledgment

1. The amendment filed on 7/29/2005 in response to the Office action mailed on 5/10/2005 has been entered. The present Office action is made with all the suggested amendments being fully considered. Accordingly, pending in this Office action are claims 26-38 and 40-46.

Election/Restrictions

2. Applicant's election without traverse of group II (claims 26-46) in the reply filed on 03/01/2005 is acknowledged.

Priority

3. Receipt is acknowledged of papers submitted under 35 U.S.C. 119(a)-(d), which papers have been placed of record in the file.

Claim Rejections - 35 USC § 102

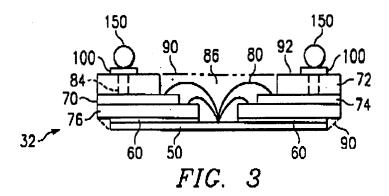
4. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 5. Claims 26, 27, 30, 32, 36 and 40 are rejected under 35 U.S.C. 102(b) as being anticipated by Yew et al. (US 6,049,129).
- 6. Regarding claim 26, Yew (e.g. figs. 2 & 3)) shows a semiconductor assembly comprising: at least one semiconductor die having a plurality of bond pads 120 formed

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on active surface thereof; at least one anisotropically conductive layer 70 comprising a plurality of laterally isolated conductive elements 84 disposed in a dielectric material 72 (i.e. FR-4) and having an upper end exposed therethrough attached to the active surface by the adhesive layer 60; a plurality of conductive bumps 150 on the at least one anisotropically conductive layer with each of eh plurality of conductive bumps in contact with at least one conductive element of the plurality; and wire bonds 80 between the bond pads and the conductive bumps.



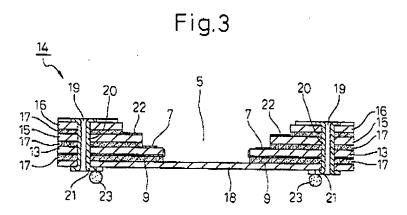
- 7. Regarding claim 27, Yew shows that the anisotropically conductive layer comprises conductive elements in the form of discrete metal columns embedded in a polymeric material (col. 3/lls. 60-65).
- 8. Regarding claim, 30 Yew shows that the polymeric material comprises a film.
- 9. Regarding claim 32, Yew discloses that the anisotropically conductive layer is attached to the active surface by an adhesive 60 (col. 3/lls. 47-68).
- 10. Regarding claim 36, Yew discloses that the conductive bumps are attached to the conductive element by metallurgical bonds (col. 5/lls. 21-25). Note that a metallurgical bond is formed when a solder bump is attached to the pad by solder reflow.

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11. Regarding claim 40, Yew teaches that the semiconductor die is in the form of singulated die.

Claim Rejections - 35 USC § 103

- 12. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 13. Claim 31 is rejected under 35 U.S.C. 103(a) as being unpatentable over Yew et al. (US 6,049,129) in view of Sato (US 5,858,816).
- 14. Regarding claim 31, Yews shows most aspect of the instant invention except for a conductive element comprising at least one of tungsten, aluminum, copper, silver, gold, and alloys thereof. Nevertheless, Sato (e.g. fig. 3) shows a structure analogous to the conductive layer 72 disclosed by Yews were the conductive element 20 is made of copper.

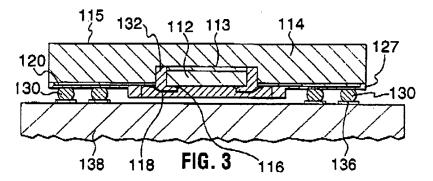


It would have been obvious to one of ordinary skill in the art at the time the invention was made to make the conductive element disclosed by Yew of copper as

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suggested by Sato because copper has a high conductivity, is easily fabricated, and has an excellent corrosion resistance in natural environments.

- 15. Claims 33 and 34 are rejected under 35 U.S.C. 103(a) as being unpatentable over Yew et al. (US 6,049,129) in view of Marcantonio (US 5,796,170).
- 16. Regarding claim 33, Yew teaches most aspects of the instant invention including semiconductor substrate assembly attached to a substrate (col. 2/29-32). Yew does not disclose a substrate having a plurality of terminal pads on a surface thereof; and wire bonds extending between the plurality of conductive bumps and the plurality of terminal pads. Nevertheless, Marcantonio (e.g. fig. 3) teaches an analogous embodiment that includes a substrate 138 having a plurality of terminal pads 136 on a surface thereof, and bonds 118 extending between the plurality of conductive bumps and the plurality of terminal pads. This type of substrate serves a variety of functions. Foremost, it contains the wiring required to interconnect the components electrically, acts as the primary structure to supports those components and is also used to conduct away heat generated by the components.



It would have been obvious to one of ordinary skill in the art at the time the invention was made to include a substrate having a plurality of terminal pads on a

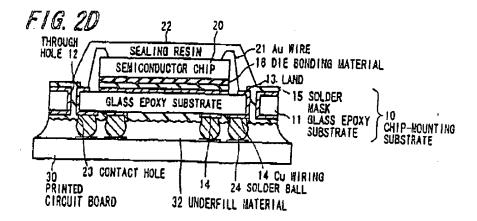
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surface thereof in Yew's invention as suggested by Marcantonio to provide support, a interconnection medium and a heat transfer path. Note that in this combination the wire bonds are located between the plurality of conductive bumps and the plurality of terminal pads.

- 17. Regarding claim 34, Marcantonio shows that the substrate comprises a circuit board (e.g. fig. 4).
- 18. Claim 35 is rejected under 35 U.S.C. 103(a) as being unpatentable over Yew et al. (US 6,049,129) in view of Kobayashi (US 6,806,560).
- 19. Regarding claim 35, Yew teaches most aspects of the instant invention including semiconductor substrate assembly attached to a substrate (col. 2/29-32). Also, Yew shows a dielectric layer 86 over the at least one semiconductor die, the bond pads and the wire pads. Yew does not teach that the dielectric layer is extended to cover the conductive bumps. Nevertheless, Kobayashi (e.g. fig. 2D) teaches a dielectric layer 32 at the outer surface of a dielectric layer 41 and covering conductive bumps 24. According to Kobayashi, this type of embodiment absorbs a stress caused by a difference in the thermal expansion coefficient between the die mounting structure and the substrate and impacts caused by fallings to secure the reliability of soldered jointed portions (col. 1/lls. 34-41).

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It would have been obvious to one of ordinary skill in the art at the time the invention was made to cover the outer surface and the conductive bumps disclosed by Yew in order to absorb a stress caused by a difference in the thermal expansion coefficient between the die mounting structure and a substrate and impacts caused by fallings to secure the reliability of soldered jointed portions as suggest by Kobayashi.

- 20. Claim 37 is rejected under 35 U.S.C. 103(a) as being unpatentable over Yew et al. (US 6,049,129) in view of Wu (US 6,727,519).
- 21. Regarding claim 37, Yew discloses that the wire bonds are made of gold (col. 6/lls. 60-64). Yew does not disclose that the conductive bumps are made of gold. Nevertheless, Wu teaches that gold is a suitable material for making conductive bumps (col. 3/lls. 21-23). It would have been obvious to one of ordinary skill in the art at the time the invention was made to make the conductive bump disclosed by Yew of gold as suggested by Wu because gold is highly resistant to many corrosive environments, is tarnish resistant, is highly resistant to spark erosion and because of its thermoelectric stability.

Allowable Subject Matter

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22. Claims 38 and 41-46 are allowed.

23. Claims 28 and 29 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

Response to Arguments

24. Applicant's arguments filed 7/29/2005 have been fully considered but they are not persuasive.

- 25. Applicant argues that Yew does not teach wire bonds extending between, and thus connecting bond pads with the conductive bumps. Initially, the prior art meet the claim limitation since Yew clearly shows "wire bonds extending between the bond pads and the conductive bumps". Also, the wire bonds electrically connect the bond pads and the conductive bumps. Note that the claim does not specify the type of connection (e.g. direct, electrical connection, etc). Although the claims are interpreted in light of the specification, limitations from the specification are not read into the claims. See *In re Van Geuns*, 988 F.2d 1181, 26 USPQ2d 1057 (Fed. Cir. 1993).
- 26. Applicant argues that Yew does not show an anisotropically conductive material. It is respectfully noted that the claim does not mention that the layer per se is made of an anisotropically conductive material. The claim defines "anisotropically conductive layer" in terms of its structural elements (*i.e.*, a plurality of laterally isolated conductive elements disposed in a dielectric material and having an upper end exposed therethrough attached to the active surface) and not in terms of its composition. The conductive layer disclosed by Yew can be properly labeled as anisotropically conductive

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layer since it meets the claim definition. Furthermore, the conductive layer disclosed by Yew allows conduction of electricity in a single direction.

- 27. Applicant argues that Yew does not disclose that the columns are embedded in a polymeric material. Nevertheless, Yew teaches that the substrate is made of a polymeric material because it is made of epoxy resin (col. 3/lls. 60-65).
- 28. Applicant Yew does not disclosed a conductive layer comprising a tape or a film. Nevertheless, Yew clearly teaches that the conductive layer is made from films (col. 3/66-67 & col. 4/lls. 1-10). Furthermore, thin is a relative term.
- 29. Applicant argues that the combination of Yew and Marcantonio fails to teach or suggest wire bonds extending between the plurality of conductive bumps and the plurality of terminal pads. Nevertheless, Yew and Marcantonio teaches these limitations because Yew teaches the wire bonds whereas Marcantonio teaches bonds extending between the plurality of conductive bumps and the plurality of terminal pads.
- 30. In response to applicant's argument that the references fail to show certain features of applicant's invention, it is noted that the features upon which applicant relies (i.e., not a flip chip configuration or conductive bump not connected to a printed circuit board) are not recited in the rejected claim(s). Although the claims are interpreted in light of the specification, limitations from the specification are not read into the claims. See *In re Van Geuns*, 988 F.2d 1181, 26 USPQ2d 1057 (Fed. Cir. 1993). Applicant argues that combination is inoperative since the covered conductive bumps as claimed would be unable to make an electrical connection in a flip chip configuration. It is restfully noted that Kobayashi shows that it is possible to have conductive bumps

electrically connected to a substrate and covered at the same time by a dielectric layer.

Note that the claim is broad enough to cover bumps partially covered by a dielectric layer.

Conclusion

31. THIS ACTION IS MADE FINAL. Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

- 32. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Leonardo Andújar whose telephone number is 571-272-1912. The examiner can normally be reached on Mon through Thu from 9:00 AM to 7:30 PM EST.
- 33. If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Nathan J. Flynn can be reached on 571-272-1915. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

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34. Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic

Leonardo Andujar

Primary Exam(ne)

Business Center (EBC) at 866-217-9197 (toll-free).

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